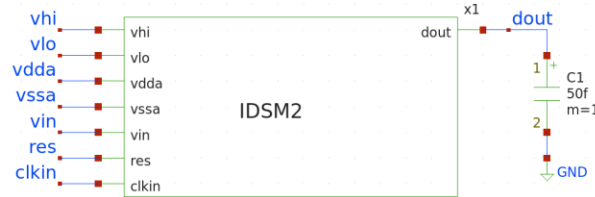
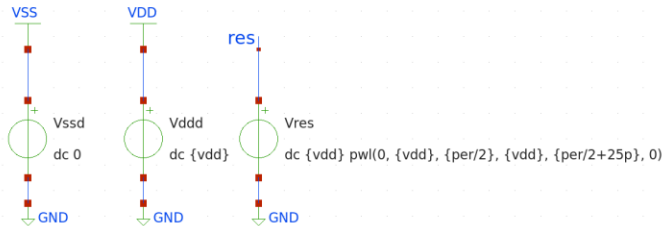


# Schematic & Layout Deliberations

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# Top-Level Testbench

## Simulating 5 input voltages:



### NGSPICE

```
.param temp=27 per=20n N=110
.param vlo=0.3 vhi=0.9 vdd=1.2 vin=0.6
.option method=gear reltol=1e-5
.ic v(x1.x3.out1p)=0
.tran 100p {per*N} uic
.meas tran iavg_ana AVG i(Vdda)
.meas tran iavg_dig AVG i(Vddd)

.control
set wr_singlescale
set wr_vecnames
option numdgt = 3
let index = 1
foreach vin_val 0.5 0.55 0.6 0.65 0.7
  alterparam vin = $vin_val
  reset
  run
  set file = {tb_idsm2_}{index}{.txt}
  wrdata $file x1.vout1 x1.vout2 dout x1.p1 x1.p2
  destroy $curplot
  let index = index + 1
end
.endc
```

### MODEL

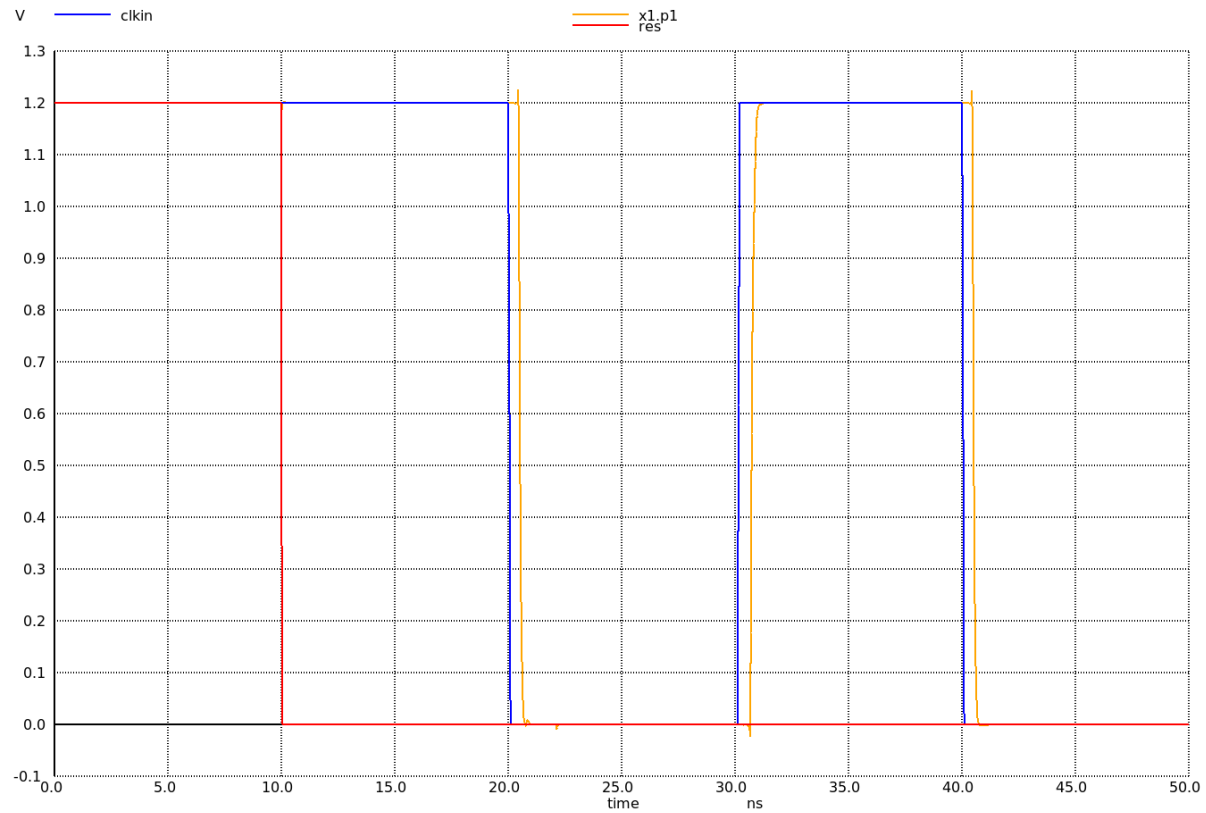
```
.lib $::SG13G2_MODELS/cornerMOSlv.lib mos_tt
.lib $::SG13G2_MODELS/cornerCAP.lib cap_typ
.inc $::PDK_ROOT/sg13g2/libs.ref/sg13g2_stdcell/spice/sg13g2_stdcell.spice
```



Boris Murmann  
/foss/designs/tb\_IDSM2.sch

2024-03-27 04:26:06

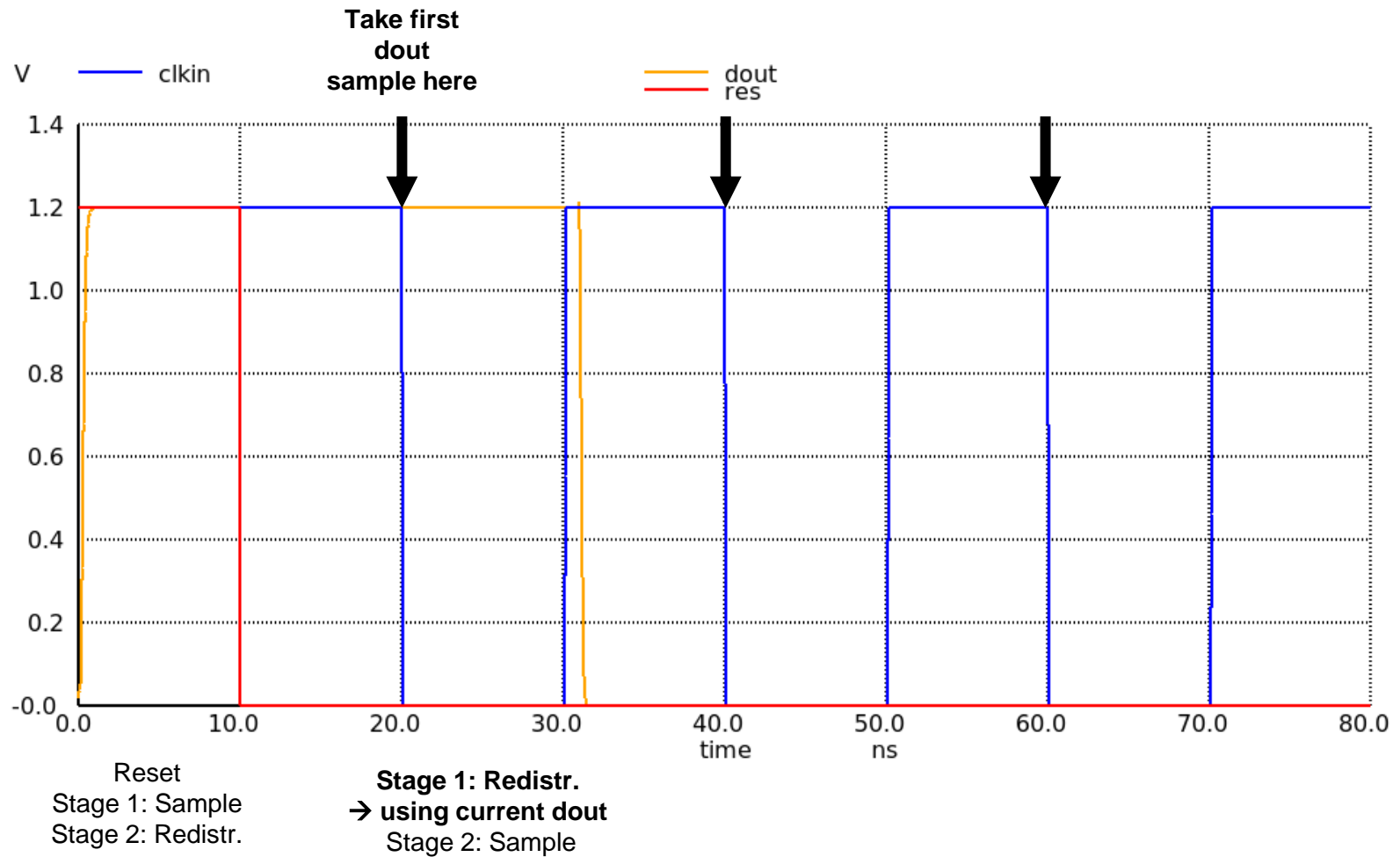
# Reset Timing



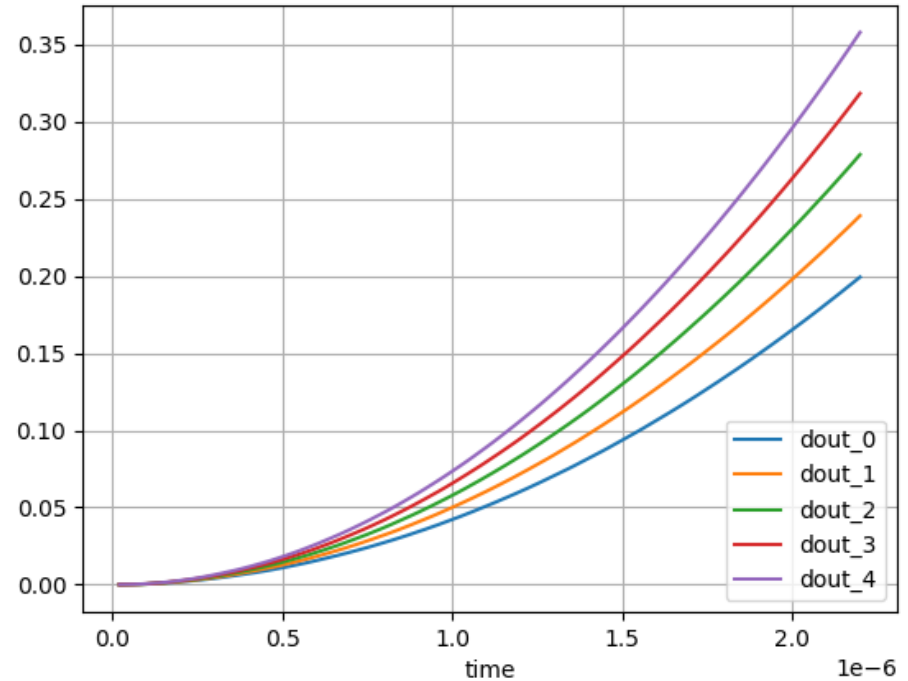
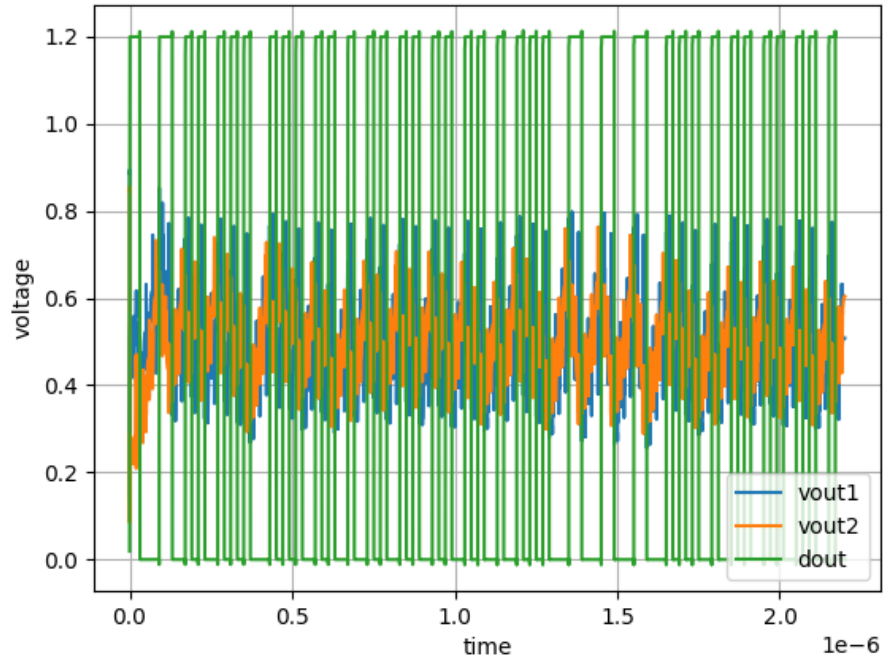
Reset

Stage 1: Sample	Stage 1: Sample	Stage 1: Redistr.
Stage 2: Redistr.	Stage 2: Redistr.	Stage 2: Sample

# Output Timing



# Output and Decimated Output for 5 Input Voltages



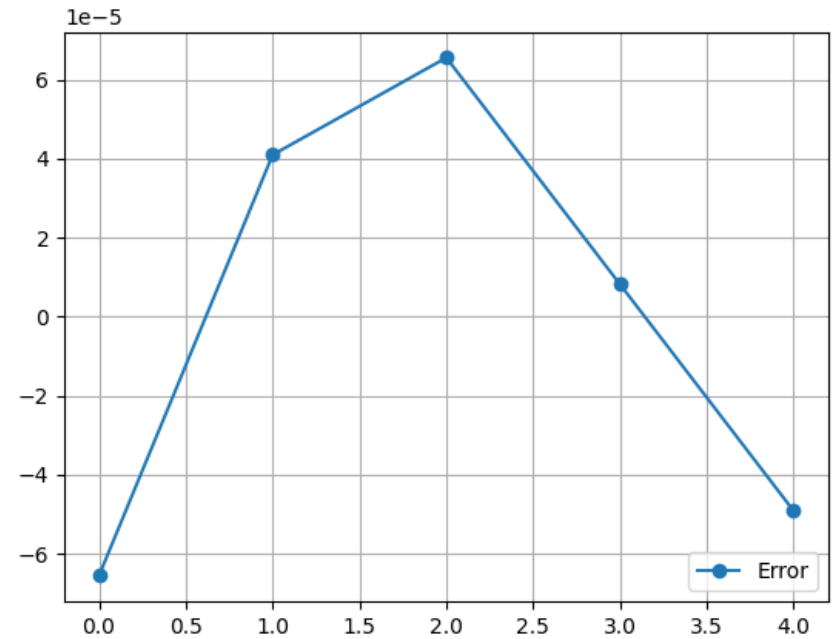
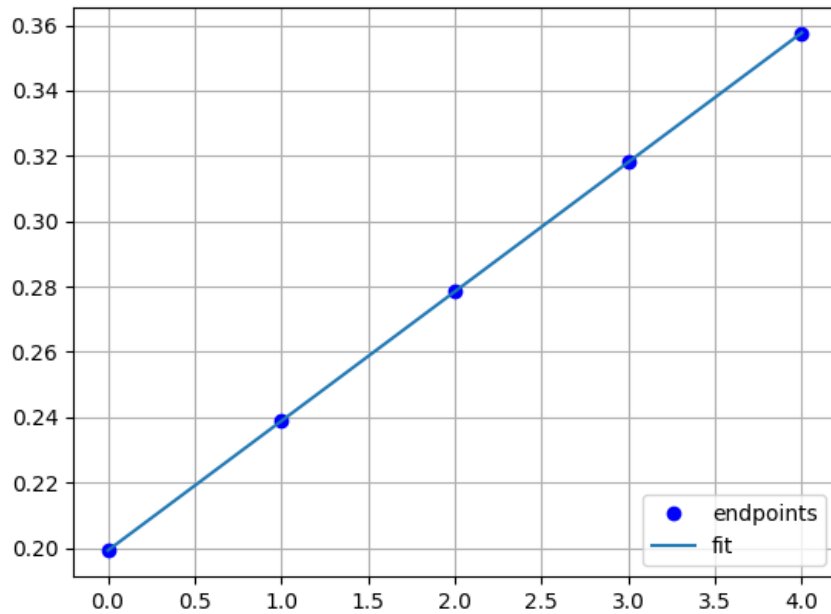
[https://github.com/bmurnann/EE628/blob/main/5\\_Design/3\\_Real\\_circuits/tb\\_IDS2.ipynb](https://github.com/bmurnann/EE628/blob/main/5_Design/3_Real_circuits/tb_IDS2.ipynb)

# Code

```
nfiles = 5
per = 20e-9
tstart = 20e-9
N = 110
out = np.zeros([5, N])
for i in range(nfiles):
    file = "./simulations/tb_idsm2_" + str(i+1) + ".txt"
    df = pd.read_csv(file, sep='\s+')
    dout = df['dout']
    t = df['time']
    ts = np.arange(tstart, tstart+N*per, per)
    interp_func = interp1d(t, dout)
    dsamp = interp_func(ts)
    dsamp[dsamp > 0.6] = 1
    dsamp[dsamp < 0.6] = 0
    csum = np.cumsum(dsamp)
    out[i,:] = np.cumsum(csum)/N/(N+1)
```

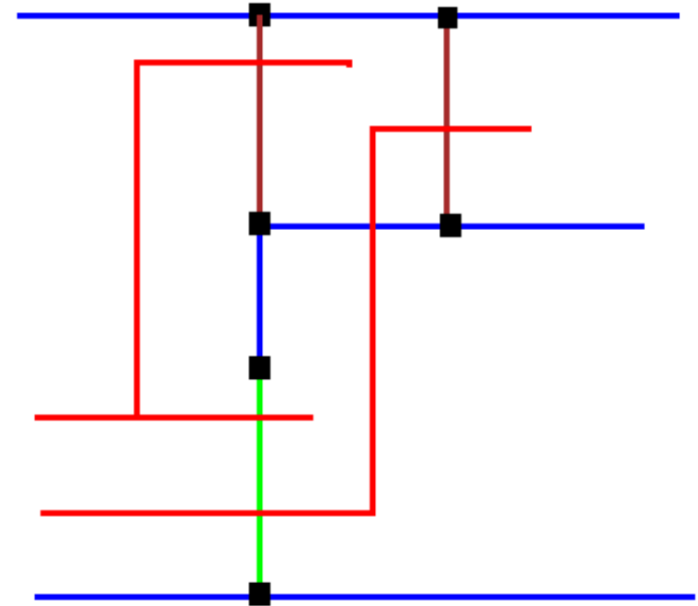
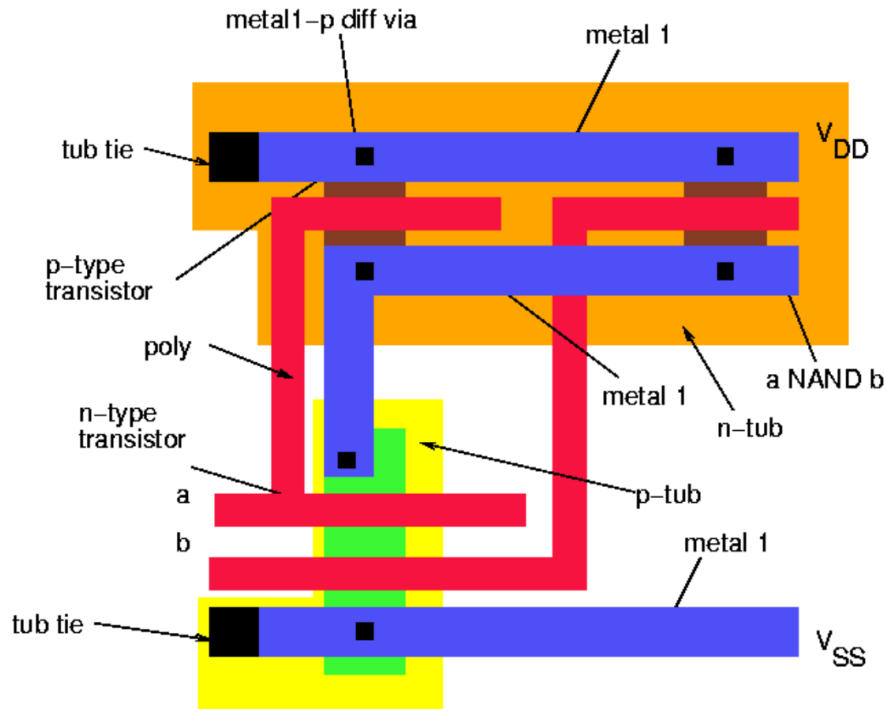
[https://github.com/bmurnann/EE628/blob/main/5\\_Design/3\\_Real\\_circuits/tb\\_IDS2.ipynb](https://github.com/bmurnann/EE628/blob/main/5_Design/3_Real_circuits/tb_IDS2.ipynb)

# Linear Fit



[https://github.com/bmurnann/EE628/blob/main/5 Design/3 Real circuits/tb IDSM2.ipynb](https://github.com/bmurnann/EE628/blob/main/5%20Design/3%20Real%20circuits/tb%20IDSM2.ipynb)

# Stick Diagrams for Cell Layout Floorplanning



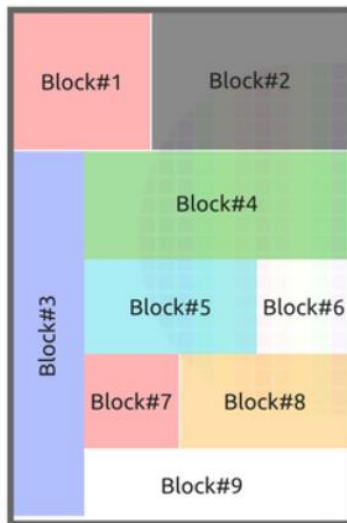
[https://users.ece.utexas.edu/~mcdermot/vlsi1/main/lectures/lecture\\_3.pdf](https://users.ece.utexas.edu/~mcdermot/vlsi1/main/lectures/lecture_3.pdf)



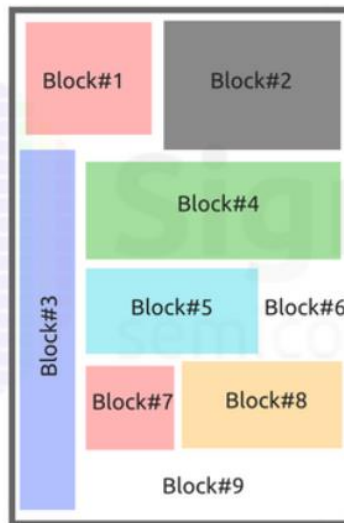
## Types of floorplan techniques used in Full Chip plan

1. Abutted (All inter block pin connections are done through FTs)
2. Non abutted (Channel based. All inter block pin connections are routed in channels)
3. Mix of both – partially abutted with some channels

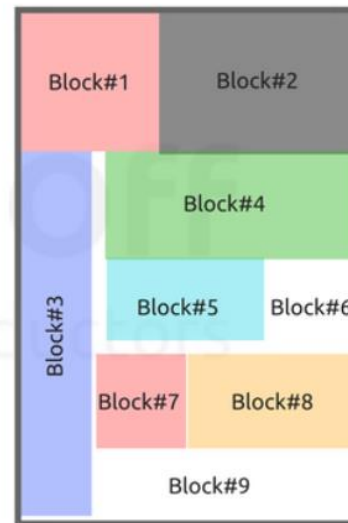
Abutted FP



Non Abutted FP



Partially abutted + Channel FP



<https://signoffsemiconductors.com/floorplan/>